Electronic Supplementary Information

Enhanced Thermoelectric Performance in Mg_{3+x}Sb_{1.5}Bi_{0.49}Te_{0.01} via Engineering Microstructure through Melt-Centrifugation

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Figure S1. Specific heat of Mg_{3.2}Sb_{1.5}Bi_{0.49}Te_{0.01} calculated by Maier-Kelley equation as a function of temperature^{1, 2}.

Fig. S2 shows the phase diagram of the Mg-Sb system. Because it contains eutectic points in two different two-phase regions (Mg-Mg₃Sb₂ and Mg₃Sb₂-Sb), the melt centrifugation technique is applicable to both Mg-excess and Sb-excess compositions. As seen from the diagram on the left side of Mg₃Sb₂ (as marked by the vertical red dotted lines in the figure), a mixture of Mg and Mg₃Sb₂ can be acquired through adding an excess amount of Mg. By subsequent heat treatment of the mixture at a temperature higher than the eutectic point (627°C), but lower than the melting point of the main Mg₃Sb₂ phase, one can get a solid Mg₃Sb₂ phase with the liquid phase. In this sense, *n*-type Mg₃Sb₂ samples with porous microstructure and dislocation arrays can be obtained by the removal of liquid Mg with centrifugal force.



Figure S2. Binary phase diagram of Mg-Sb³.

The lattice parameters of samples with starting compositions $Mg_{3.2}Sb_2$, $Mg_{3.2}Sb_{1.5}Bi_{0.49}Te_{0.01}$ and centrifuged $Mg_{3.2}Sb_{1.5}Bi_{0.49}Te_{0.01}$ samples were evaluated by using the WinCSD program (Table S1). An increase in the lattice parameters was observed by XRD phase analysis; implying successful incorporation of Bi and Te into the crystal structure of Mg_3Sb_2 . What is more, extending the time of heat treatment (from 30 to 60 min) coupled with centrifugation, leads to even further increase in lattice parameters, suggesting a slight change in the chemical composition.

Table S1 Lattice	narameters (a ar	d c snace grou	n <i>D</i> 3 <i>m</i> 1	structure tvr		fsamnles	investigated
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Starting Composition	a (Å)	c(Å)
Mg _{3.2} Sb ₂	4.560(1)	7.223(4)
$Mg_{3.2}Sb_{1.5}Bi_{0.49}Te_{0.01}$	4.582(4)	7.286(7)
MSBT_20ext_30m_c	4.613(3)	7.317(6)
MSBT_20ext_1h_c	4.596(1)	7.295(3)



Figure S3. XRD patterns (Cu-K_{α 1} radiation) of parent Mg_{3+x}Sb₂, MSBT samples and centrifuged samples before and after centrifugation process



Figure S4. a) SE image (20.0 kV HV) of MSBT_20ext_1h_c sample with elemental mapping of b) Mg, c) Sb, d) Bi,and e) BSE image (10.0 kV HV) of MSBT_20ext_30m_c sample with elemental mapping of f) Mg, g) Sb, h) Bi.



Figure S5. Rietveld fit of MSBT_20ext_1h (Cu-K_{a1} radiation). Ticks at the top and bottom mark the calculated reflection positions of the target phase Mg₃Sb₂ and Mg, respectively. The baseline corresponds to the residuals of a Rietveld refinement ($R_i = 0.06$, $R_p = 0.14$, $R_{wp} = 0.19$) based on the reported crystal structure. In the crystal structure of Mg₃Sb₂ (space group: $P^{3}m1$), there are two Mg (1*a* and 2*d*) and one Sb (2*d*) Wyckoff sites. The refinement indicates that all the Mg sites are fully occupied, while the Sb site is mixed occupied (0.74(2) Sb and 0.26(2) Bi).



Figure S6. Rietveld fit of MSBT_20ext_1h_c (Cu-K_{a1} radiation). Ticks mark the calculated reflection positions of the target phase Mg₃Sb₂. The baseline corresponds to the residuals of a Rietveld refinement (R_i = 0.08, R_p = 0.16, R_{wp} = 0.20) based on the reported crystal structure. In the crystal structure of Mg₃Sb₂ (space group: $P^{3}m^{1}$), there are two Mg (1*a* and 2*d*) and one Sb (2*d*) Wyckoff sites. The refinement indicates that all the Mg sites are fully occupied, while the Sb site is mixed occupied (0.78(2) Sb and 0.22(2) Bi).

WDS analysis was carried out for MSBT sample on 10 different spots (Figure S7. and Table S2). For this, the composition of the sample was determined to be $Mg_{3.08(1)}Sb_{1.44(2)}Bi_{0.47(1)}Te_{0.01(3)}$, which is almost the same stoichiometry as the nominal composition.



Figure S7. WDXS analysis of Mg_{3+x}Sb_{1.5}Bi_{0.49}Te_{0.01} sample was performed on 10 different, randomly-chosen spots.

	Atomic Percent	Standard Deviation	
Mg	61,6	0,2	
Sb	28,8	0,3	
Bi	9,4	0,2	
Те	0,221	0,006	
Total	100		

Table S2. WDS analysis results (average on 10 points) for the sample $Mg_{3+x}Sb_{1.5}Bi_{0.49}Te_{0.01}$.



Figure S8. Bright Field TEM images of MSBT_20ext_30m_c taken from a) out-of-plane direction and b) in-plane direction.



Figure S9. SEM images of MSBT_20ext_30m_c (a and b; 20.00 kV EHT) and MSBT_20ext_1h_c (c and d; 20.00 kV EHT) in secondary electron mode (SE).



Figure S10. SEM images of MSBT_20ext_30m_c (a and b; 20.00 kV EHT) and MSBT_20ext_1h_c (c and d; 20.00 kV EHT) in secondary electron mode (SE) after etching process.



Figure S11. Calculated weighted mobility data of MSBT (black), MSBT_46in_30m_c (red), MSBT_46ext_30m_c (blue), MSBT_20ext_30m_c (pink) and MSBT_20ext_1h_c (green) as a function of temperature.



Figure S12. Temperature dependence of the electronic thermal conductivity κ_e of MSBT (black), MSBT_46in_30m_c (red), MSBT_46ext_30m_c (blue), MSBT_20ext_30m_c (pink) and MSBT_20ext_1h_c (green) samples as a function of temperature.

Table S3. Densities and relative densities of	f spark plasma sintered and centrifuged	d samples calculated by the geometrical
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	MSBT	MSBT_46in_30m_c	MSBT_46ext_30m_c	MSBT_20ext_30m_c	MSBT_20ext_1h_c
Density (g/cm ³)	4.3	3.27	3.35	3.89	3.83
Relative	95.7	72.8	74.6	86.6	85.3
Density %					

method.

As seen in Table S3, the consolidated MSBT sample showed a high relative density of ~96%. Even though spark plasma sintering technique produced highly densified materials, centrifugation formed a porous microstructure. In this respect, after the centrifugation process, the relative densities were significantly reduced.

A glance at relative density values given in Table S3 disclose that relative density has a reverse relation with excess Mg, meaning that with increasing Mg excess amount relative density decreases. The induced porosities for the last two samples are shown in FigureS9.



Figure S13. DSC/TG analysis of melt-centrifuged MSBT_20ext_30min_c sample.



Figure S14. Temperature dependence of a) electrical resistivity, b) Seebeck coefficient, c) thermal conductivity and d) thermoelectric figure of merit *zT* values of MSBT_20ext_30m_c sample. The stability of melt-centrifuged sample is shown by heating-cooling cycles for the same sample.

References

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